

Abstract Submitted
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Electronic Excitations and Optical Properties of RFeO₃ (R = Lu and Yb) Thin Films¹ RAM RAI, DEVLIN MCKENNA, CAITLIN HORVATITS, JULIANNA DU HART, Physics Department, SUNY Buffalo State, 1300 Elmwood Ave, Buffalo, NY 14222 — We present structural, electronic, and optical properties of multiferroic RFeO₃ (R = Lu and Yb) thin films, deposited on single crystal sapphire and YSZ substrates under the various growth conditions using RF Magnetron Sputtering. Growth temperature and annealing are found to be critical to stabilize hexagonal RFeO₃ thin films. Based on the X-ray diffraction data, annealing above ~900 °C has been found to change the crystal structure of RFeO₃ from a metastable hexagonal to an orthorhombic structure. Optical spectroscopy in the 0.5-6.5 eV range has been used to study the optical and electronic excitations of the RFeO₃ thin films. The electronic excitations dominated by Fe d to d on-site as well as O 2p to Fe 3d, R 6s, and R 5d charge-transfer transitions for hexagonal and orthorhombic RFeO₃ are distinctly different, consistent with the excitations from the FeO₅ and FeO₆ building blocks for hexagonal and orthorhombic RFeO₃, respectively. Further, the optical spectra exhibit strong temperature dependence with an anomaly at the magnetic transition, indicating a structural distortion. We'll also present the magnetic measurements data on the RFeO₃ thin films.

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